Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

HEISE ET AL.

Examiner

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Chen, Xiaoliang

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Art Unit

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Class	Subclass	Date	Examiner	
361	104, 760-763, 833, 834	05-17-07	xc	
174	250, 261	05-17-07	xc	
337	227, 290-297	05-17-07	XC	

SEARCH NOTES

Search Notes	Date	Examiner	
Puls, Inventor,	05-16-07	xc	
EAST / Ref Proir Art, Foreward/Backward, USPAT, PGPUB, DERWENT, IBM-TDB, ITIC-On line, IEEE Xplore and text	05-16-07	xc	
Consulted Tuan Dinh	05-16-07	xc	
Updated East Serach	10-03-07	xc	
Updated East Search	1-22-08	XC	

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